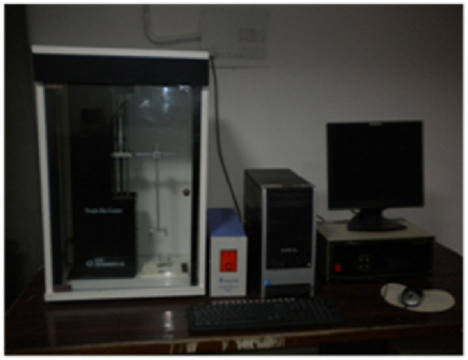
RESEARCH FACILITIES

Scanning Electron Microscope

FT-IR Spectrometer RX-1

Rigaku Miniflex X-ray diffractometer

UV- VIS Spectrophotometer



Single Dip Coating system

HP-4263B LCR meter with external bias Supply, Hioki LCR tester

Automatic PE Loop Tracer system

Atomic Force Microscopy

Dielectric Setup & Spin Coating Units

Dielectric Measurement setup

Thermal evaporation Unit

Differential Scanning Calorimetry